



Contribution ID: 1

Type: **not specified**

Neutron and x-ray reflectometry for the study of thin films and interfaces

Neutron and x-ray reflectometry are complementary methods that allow the study of thin films and interfaces. I will discuss the basic principles of reflectometry experiments and data analysis. From specular reflectivity density profiles long the normal of interfaces can be extracted, while off-specular and grazing incidence scattering provides information about in-plane correlations. Examples in hydrogen storage, magnetism and polymer science will be presented.

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